


<b>Search Notes</b> 	<b>Application/Control No.</b> 10584876	<b>Applicant(s)/Patent Under Reexamination</b> BONNET ET AL.
	<b>Examiner</b> Jessica Paul	<b>Art Unit</b> 1796

### SEARCHED

Class	Subclass	Date	Examiner
522	001	2/27/2009	/JMP/
522	001	9/29/2009	/JMP/
525	274, 276	9/29/2009	/JMP/
522	114, 134	8/23/2010	/JMP/
525	274, 276	8/23/2010	/JMP/
522	114, 134	1/15/2011	/JMP/
525	274, 276	1/15/2011	/JMP/
522	114, 134	7/1/2011	/JMP/
525	274, 276	7/1/2011	/JMP/
522	114, 134	12/17/2011	/JMP/
525	274, 276	12/17/2011	/JMP/

### SEARCH NOTES

Search Notes	Date	Examiner
See EAST Search History	2/27/2009	/JMP/
Inventive Entity Search (eDAN/PALM)	2/27/2009	/JMP/
STIC Structure Search	2/27/2009	/JMP/
Updated EAST search	9/29/2009	/JMP/
Updated inventive entity search (eDAN/PALM)	9/29/2009	/JMP/
Consulted with Mike Pepitone	9/29/2009	/JMP/
Updated EAST search	8/23/2010	/JMP/
Updated inventive entity search (eDAN/PALM)	8/23/2010	/JMP/
Updated EAST search	1/15/2011	/JMP/
Updated inventive entity search (eDAN/PALM)	1/15/2011	/JMP/
Updated EAST search	7/1/2011	/JMP/
Updated inventive entity search (eDAN/PALM)	7/1/2011	/JMP/
Updated EAST search	12/17/2011	/JMP/
Updated inventive entity search (eDAN/PALM)	12/17/2011	/JMP/
Consulted with Mark Eashoo	12/17/2011	/JMP/

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
522	114, 134	12/17/2011	/JMP/

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**INTERFERENCE SEARCH**

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
525	274, 276	12/17/2011	/JMP/

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